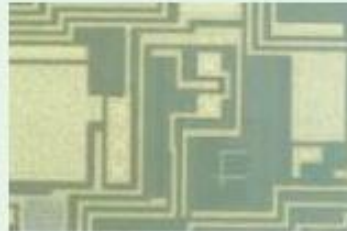


Specifications

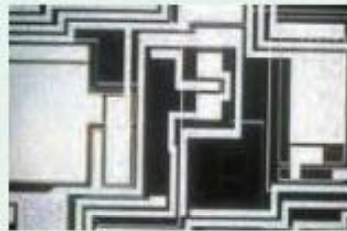
Main unit	Reflected illumination : Köehler illumination with aperture diaphragm (centering mechanism) and field stop 12V/100W halogen lamp (continuously variable brightness adjustment) with filter mounting (2-slot), with BF/DF switching slide (378-321, 378-323, 378-325, 378-327 only) Transmitted illumination : 12V/100W fibre-optic illumination (continuously variable brightness, adjustment) with aperture diaphragm (378-323, 378-324, 378-326, 378-327 only)
Power turret	Inward type with 4 lens mounts
Workstage	Travel stroke : 356 x 306 mm with X/Y axis fine feed knobs, and coarse travel handle
Optical tube	Type : Trinocular Siedentopf (erect image) Field number : 24 Intermediate image mag. : 1 Optical pass ratio and Pupil distance : 50/50, adjustment range : 51 - 76 mm
Dimensions	Main unit : 360 x 803 x 568,5 mm Workstage : 700 x 400 mm
Power supply	100/240V AC, 50/60Hz
Mass	Approx. 50 kg including workstage



Polarized light observation : Observing only the filtered light that vibrates in one direction. Used for observing materials with special optical characteristics, such as mineral and liquid crystal.



Differential interference observation : Effective in detecting fine scratches and steps on the surface of metal, liquid crystal, and semiconductors.



Dark field observation : Observing only the scattered light by shutting down the direct light to the objectives. The scratches and dust that cannot be viewed in the bright view field can be observed by this method in high-contrast.